

Advanced technical education in the age of cyber physical systems

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High-level modeling and testing of multiple control faults in digital systems

Jasnetski, Artjom; Oyeniran, Adeboye Stephen; Tšertov, Anton; Schölzel, Mario; **Ubar, Raimund-Johannes** Formal proceedings of the 2016 IEEE 19th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 20-22, 2016, Košice, Slovakia 2016 / [6] p. : ill <http://dx.doi.org/10.1109/DDECS.2016.7482445>

Multiple fault testing in systems-on-chip with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Schölzel, Mario; Vierhaus, Heinrich Theodor Proceedings of 2015 10th International Design & Test Symposium (IDT) : Dead Sea, Jordan, 14-16 December 2015 2015 / p. 66-71 : ill <http://dx.doi.org/10.1109/IDT.2015.7396738>